SN54HCT373 供应商

SN54HCT373, SN74HCT373 OCTAL TRANSPARENT D-TYPE LATCHES WITH 3-STATE OUTPUTS SCLS009B – MARCH 1984 – REVISED MAY 1997

- Inputs Are TTL-Voltage Compatible
- Eight High-Current Latches in a Single Package
- High-Current 3-State True Outputs Can Drive up to 15 LSTTL Loads
- Full Parallel Access for Loading
- Package Options Include Plastic Small-Outline (DW) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

These 8-bit latches feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The eight latches of the 'HCT373 are transparent D-type latches. While the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When LE is taken low, the Q outputs are latched at the levels that were set up at the D inputs.

An output-enable (\overline{OE}) input places the eight outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

OE does not affect the internal operations of the latches. Old data can be retained or new data can be entered while the outputs are off.

The SN54HCT373 is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74HCT373 is characterized for operation from -40° C to 85° C.



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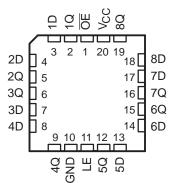
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



SN54HCT373 ... J OR W PACKAGE SN74HCT373 ... DW OR N PACKAGE (TOP VIEW)

	`		, ,
ŌE	1	U ₂₀	vcc
1Q	2	19	
1D	[3	18] 8D
2D	4	17]7D
2Q	5	16] 7Q
3Q	6	15] 6Q
3D	[7	14] 6D
4D	8	13] 5D
4Q	9	12] 5Q
GND	10	11	LE
			-

SN54HCT373 . . . FK PACKAGE (TOP VIEW)

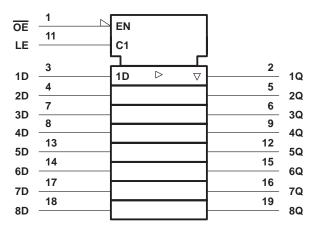


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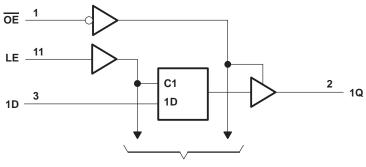
	FUNCTION TABLE (each latch)											
	INPUTS	OUTPUT										
OE	LE	D	Q									
L	Н	Н	Н									
L	н	L	L									
L	L	Х	Q ₀									
Н	Х	Х	Z									

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



To Seven Other Channels



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absolute maximum ratings over operating free-air temperature range[†]

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1)	
Output clamp current, I_{OK} (V _O < 0 or V _O > V _{CC}) (see Note 1)	
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	±35 mA
Continuous current through V _{CC} or GND	
Package thermal impedance, θ_{JA} (see Note 2): DW package	
N package	
Storage temperature range, T _{stg}	–65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

recommended operating conditions

			SN54HCT373			SN	UNIT		
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	V_{CC} = 4.5 V to 5.5 V	2			2			V
VIL	Low-level input voltage	V_{CC} = 4.5 V to 5.5 V	0		0.8	0		0.8	V
VI	Input voltage		0		VCC	0		VCC	V
Vo	Output voltage		0		VCC	0		VCC	V
tt	Input transition (rise and fall) time		0		500	0		500	ns
TA	Operating free-air temperature		-55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		Vaa	Т	A = 25°C	;	SN54H	ICT373	SN74HCT373		UNIT
PARAMETER	TEST CO	NDITIONS			TYP	MAX	MIN	MAX	MIN	MAX	UNIT
Vou	VI = VIH or VIL	I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		V
∨он	VI = VIH OL VIL	I _{OH} =6 mA	4.5 V	3.98	4.3		3.7		3.84		v
Vei	VI = VIH or VIL	I _{OL} = 20 μA	4.5 V		0.001	0.1		0.1		0.1	- V
VOL	VI = VIH OL VIL	I _{OL} = 6 mA	4.5 V		0.17	0.26		0.4		0.33	
li	AI = ACC or 0		5.5 V		±0.1	±100		±1000		±1000	nA
I _{OZ}	AO = ACC or 0		5.5 V		±0.01	±0.5		±10		±5	μΑ
ICC	$V_I = V_{CC} \text{ or } 0,$	I <mark>O</mark> = 0	5.5 V			8		160		80	μΑ
∆I _{CC} ‡	One input at 0.5 V of Other inputs at 0 or	,	5.5 V		1.4	2.4		3		2.9	mA
Ci			4.5 V to 5.5 V		3	10		10		10	pF

[‡]This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.



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timing requirements over recommended operating free-air temperature range (unless otherwise noted)

		Vaa	T _A = 2	25°C	SN54H	СТ373	SN74H	CT373	UNIT
		Vcc	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
t Dulas dura	Pulse duration, LE high	4.5 V	20		30		25		20
tw	Puise duration, LE nigh	5.5 V	17		27		23		ns
	Setup time, data before LE \downarrow	4.5 V	10		15		13		
t _{su}		5.5 V	9		14		12		ns
4	Hold time, data after LE \downarrow	4.5 V	10		10		10		ns
th		5.5 V	10		10		10		

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	то		T _A = 25°C			СТ373	SN74HCT373		UNIT
PARAMETER	(INPUT)	(INPUT) (OUTPUT)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
	D	Q	4.5 V		25	35		53		44	
• .	D	Q	5.5 V		21	32		48		40	ns
^t pd	LE	Apy O	4.5 V		28	35		53		44	115
	LC	Any Q	5.5 V		25	32		48		40	
	OE	Amy O	4.5 V		26	35		53		44	ns
t _{en}	OE	Any Q	5.5 V		23	32		48		40	115
÷	OE	Any Q	4.5 V		23	35		53		44	ns
^t dis	ÛE	E Any Q	5.5 V		22	32		48		40	115
+.		Any Q	4.5 V		10	12		18		15	ns
tt			5.5 V		9	11		16		14	115

switching characteristics over recommended operating free-air temperature range, $C_L = 150 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	ТО Исс		₄ = 25°C	;	SN54H	CT373	SN74H	СТ373	UNIT
PARAMETER	(INPUT)	(OUTPUT)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX 65 59 65 59 59	UNIT
	D	Q	4.5 V		32	52		79		65	
. .	D	Q	5.5 V		27	47		71		59	
^t pd	LE	Any Q	4.5 V		38	52		79		65	ns
			5.5 V		36	47		71		59	
	OE	Any Q	4.5 V		33	52		79		65	ns
ten			5.5 V		28	47		71		59	115
4		Any O	4.5 V		18	42		63		53	
tt		Any Q	5.5 V		16	38		57		48	ns

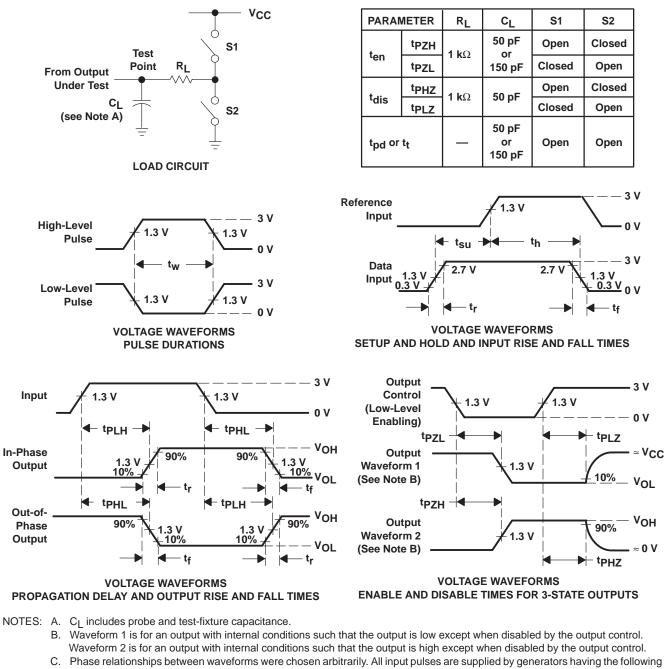
operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
Cpd	Power dissipation capacitance per latch	No load	50	pF

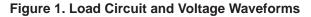


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PARAMETER MEASUREMENT INFORMATION



- characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_r = 6 ns, t_f = 6 ns.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. tPLZ and tPHZ are the same as tdis.
- F. tp71 and tp7H are the same as ten.
- G. tpLH and tpHL are the same as tpd.





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